

Impact of aging degradation on the radiation susceptibility of advanced technology nodes

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Most reliability evaluations of radiation effects for advanced technology nodes are conducted on fresh circuits, leaving the coupled effect of radiation and aging degradation unknown. A test vehicle (ProArray) of programmable arrays of transistors and shift-register chains was specially designed to investigate the impact of aging degradation mechanisms on the radiation susceptibility of 28 nm UTBB FD-SOI technology. The results and analysis of several irradiation tests will be presented.

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